TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7SZ32F,TC7SZ32FU

#### 2 Input OR Gate

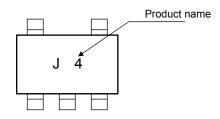
#### **Features**

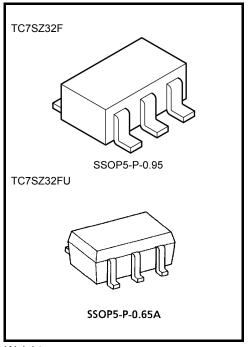
- High output drive: ±24 mA (min) at V<sub>CC</sub> = 3 V
- Super high speed operation: tpd=2.4 ns (typ.)

at  $V_{CC} = 5 \text{ V}$ , 50 pF

- Operation voltage range: V<sub>CC (opr)</sub> = 1.8~5.5 V
- 5.5-V tolerant inputs
- 5.5-V power down protection output
- Matches the performance of TC74LCX series when operated at 3.3- V V<sub>CC</sub>

#### Marking





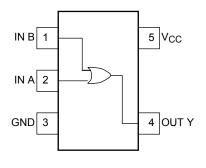
Weight

SSOP5-P-0.95 : 0.016 g (typ.) SSOP5-P-0.65A : 0.006 g (typ.)

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V <sub>CC</sub>	-0.5~6	V	
DC input voltage	V <sub>IN</sub>	-0.5~6	V	
DC output voltage	V <sub>OUT</sub>	-0.5~6	V	
Input diode current	I <sub>IK</sub>	-20	mA	
Output diode current	lok	-20	mA	
DC output current	lout	±50	mA	
DC V <sub>CC</sub> /ground current	Icc	±50	mA	
Power dissipation	PD	200	mW	
Storage temperature	T <sub>stg</sub>	-65~150	°C	
Lead temperature (10s)	TL	260	°C	

### Pin Assignment (top view)



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).



## **Logic Diagram**



### **Truth Table**

Inp	out	Output		
Α	В	Y		
L	L	L		
L	Н	Н		
Н	L	Н		
Н	Н	Н		

## **Operating Ranges**

Characteristics	Symbol	Rating	Unit	
Supply voltage	Vcc	1.8~5.5	V	
Supply voltage		1.5~5.5 (Note 1)	V	
Input voltage	V <sub>IN</sub>	0~5.5	V	
Output voltage	V <sub>OUT</sub>	0~5.5 (Note 2)	V	
		0~V <sub>CC</sub> (Note 3)	V	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
Input rise and fall time	dt/dv	$0\sim20~(V_{CC}=1.8~V,~2.5~V\pm0.2~V)$		
		$0 \sim 10 \; (V_{CC} = 3.3 \; V \pm 0.3 \; V)$	ns/V	
		$0~5~(V_{CC} = 5.5~V \pm 0.5~V)$		

Note 1: Data retention only

Note 2:  $V_{CC} = 0 V$ 

Note 3: High or Low state

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics Symbol Test Condition		ot Condition		Ta = 25°C			Ta = -40~85°C		Unit	
		l le	V <sub>CC</sub> (V)		Min	Тур.	Max	Min	Max	Unit
High-level input	V <sub>IH</sub>			1.8	V <sub>CC</sub> × 0.88	_	_	V <sub>CC</sub> × 0.88	_	V
voltage		2.3~5.5		V <sub>CC</sub> × 0.75	_	_	V <sub>CC</sub> × 0.75	_	V	
Low-level input	V			1.8	_		V <sub>CC</sub> × 0.12	_	V <sub>CC</sub> × 0.12	V
voltage			_	2.3~5.5		l	V <sub>CC</sub> × 0.25	_	V <sub>CC</sub> × 0.25	V
				1.8	1.7	1.8	_	1.7	_	
			I <sub>OH</sub> = -100 μA	2.3	2.2	2.3	_	2.2	_	
			10Η = -100 μΛ	3.0	2.9	3.0	_	2.9	_	
High-level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub>		4.5	4.4	4.5		4.4	_	V
output voltage	VOH	or V <sub>IL</sub>	$I_{OH} = -8 \text{ mA}$	2.3	1.9	2.15		1.9	_	
			I <sub>OH</sub> = -16 mA	3.0	2.4	2.8		2.4	_	
			I <sub>OH</sub> = -24 mA	3.0	2.3	2.68		2.3	_	
			I <sub>OH</sub> = -32 mA	4.5	3.8	4.2		3.8	_	
				1.8	_	0	0.1	_	0.1	
			100	2.3	_	0	0.1	_	0.1	
		$I_{OL} = 100 \mu A$	3.0	_	0	0.1	_	0.1		
Low-level	Va	V <sub>IN</sub> = V <sub>IL</sub>		4.5	_	0	0.1	_	0.1	.,
output voltage V <sub>OL</sub> V	VIN = VIL	I <sub>OL</sub> = 8 mA	2.3	_	0.1	0.3	_	0.3	V	
		I <sub>OL</sub> = 16 mA	3.0	_	0.15	0.4	_	0.4		
		I <sub>OL</sub> = 24 mA	3.0	_	0.22	0.55	_	0.55		
	I <sub>OL</sub> = 32 mA		4.5	_	0.22	0.55	_	0.55		
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V	V <sub>IN</sub> = 5.5 V or GND		_		±1	_	±10	μΑ
Power off leakage current	I <sub>OFF</sub>	V <sub>IN</sub> or V <sub>OL</sub>	V <sub>IN</sub> or V <sub>OUT</sub> = 5.5 V		_		1	_	10	μΑ
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	2	_	20	μА

### AC Characteristics (unless otherwise specified, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40~85°C		- Unit	
Characteristics	Symbol		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Offic
Propagation delay time	t <sub>р</sub> LH t <sub>р</sub> HL	$C_L = 15 \text{ pF},$ $R_L = 1 \text{ M}\Omega$	1.8	2.0	4.6	10.0	2.0	10.5	- ns
			$2.5 \pm 0.2$	0.8	3.0	7.0	8.0	7.5	
			$3.3 \pm 0.3$	0.5	2.4	4.7	0.5	5.0	
			$5.0 \pm 0.5$	0.5	1.9	4.1	0.5	4.4	
		$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	$3.3 \pm 0.3$	1.5	3.0	5.2	1.5	5.5	
			$5.0\pm0.5$	0.8	2.4	4.5	0.8	4.8	
Input capacitance	C <sub>IN</sub>	_	0~5.5	_	4	_	_		pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 4)	3.3		20		_		pF
			5.5		26		_		

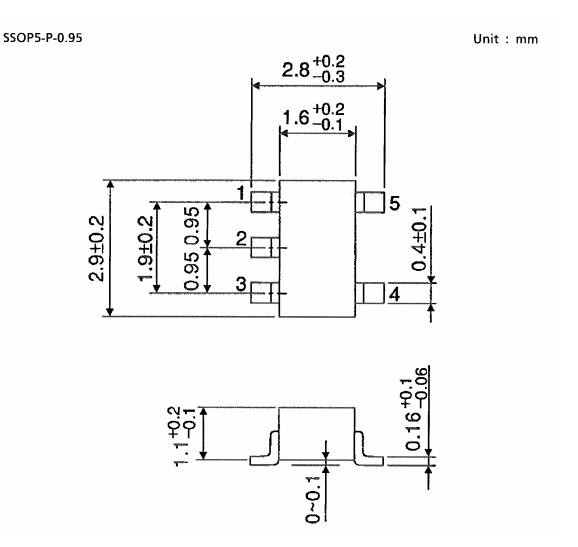
Note 4: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 



## **Package Dimensions**

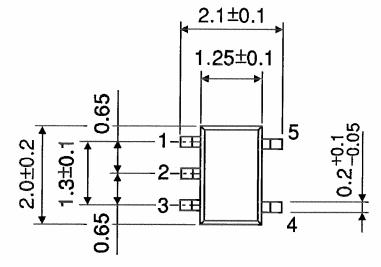


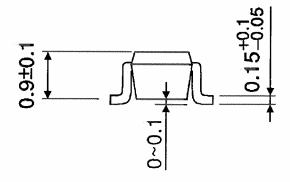
Weight: 0.016 g (typ.)

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## **Package Dimensions**

SSOP5-P-0.65A Unit: mm





Weight: 0.006 g (typ.)

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20070701-EN GENERAL

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